

MOS FIELD EFFECT TRANSISTOR NP109N04PUG

SWITCHING N-CHANNEL POWER MOS FET

DESCRIPTION

The NP109N04PUG is N-channel MOS Field Effect Transistor designed for high current switching applications.

ORDERING INFORMATION

PART NUMBER	LEAD PLATING	PACKING	PACKAGE		
NP109N04PUG-E1-AY Note					
NP109N04PUG-E2-AY Note	Pure Sn (Tin)	Tape 800 p/reel	TO-263 (MP-25ZP) typ. 1.5 g		

Note Pb-free (This product does not contain Pb in external electrode).

FEATURES

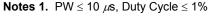
• Super low on-state resistance $R_{DS(on)}$ = 2.3 $m\Omega$ MAX. (Vgs = 10 V, Ip = 55 A)

• High current rating ID(DC) = ±110 A

(TO-263)

ABSOLUTE MAXIMUM RATINGS (TA = 25°C)

Drain to Source Voltage (V _{GS} = 0 V)	VDSS	40	V
Gate to Source Voltage (V _{DS} = 0 V)	Vgss	±20	V
Drain Current (DC) (Tc = 25°C)	I _{D(DC)}	±110	Α
Drain Current (pulse) Note1	I _{D(pulse)}	±440	Α
Total Power Dissipation (Tc = 25°C)	P _{T1}	220	W
Total Power Dissipation (T _A = 25°C)	P _{T2}	1.8	W
Channel Temperature	Tch	175	°C
Storage Temperature	Tstg	-55 to +175	°C
Repetitive Avalanche Current Note2	IAR	60	Α
Repetitive Avalanche Energy Note2	Ear	360	mJ



2. T_{ch} \leq 150°C, V_{DD} = 20 V, R_G = 25 Ω , V_{GS} = 20 \rightarrow 0 V

THERMAL RESISTANCE

Channel to Case Thermal Resistance	$R_{th(ch-C)}$	0.68	°C/W
Channel to Ambient Thermal Resistance	Rth(ch-A)	83.3	°C/W

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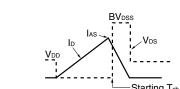
<R><R><R><R>

ELECTRICAL CHARACTERISTICS (TA = 25°C)

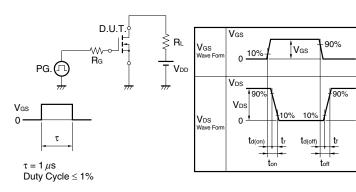
CHARACTERISTICS	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Zero Gate Voltage Drain Current	IDSS	V _{DS} = 40 V, V _{GS} = 0 V			1	μΑ
Gate Leakage Current	Igss	V _{GS} = ±20 V, V _{DS} = 0 V			±100	nA
Gate to Source Threshold Voltage	V _{GS(th)}	V _{DS} = V _{GS} , I _D = 250 μA	2.0	3.0	4.0	V
Forward Transfer Admittance	yfs	V _{DS} = 10 V, I _D = 55 A	31	63		S
Drain to Source On-state Resistance	R _{DS(on)}	V _{GS} = 10 V, I _D = 55 A		1.7	2.3	mΩ
Input Capacitance	Ciss	V _{DS} = 25 V,		10500	15750	pF
Output Capacitance	Coss	V _{GS} = 0 V,		980	1470	pF
Reverse Transfer Capacitance	Crss	f = 1 MHz		630	1140	pF
Turn-on Delay Time	t _{d(on)}	V _{DD} = 20 V, I _D = 55 A,		47	103	ns
Rise Time	tr	V _{GS} = 10 V,		35	70	ns
Turn-off Delay Time	t d(off)	$R_G = 0 \Omega$		90	180	ns
Fall Time	tr			35	70	ns
Total Gate Charge	Q _G	V _{DD} = 32 V,		180	270	nC
Gate to Source Charge	Q _{GS}	V _{GS} = 10 V,		44		nC
Gate to Drain Charge	Q _{GD}	I _D = 110 A		64		nC
Body Diode Forward Voltage	V _{F(S-D)}	I _F = 110 A, V _{GS} = 0 V		0.9	1.4	V
Reverse Recovery Time	trr	I _F = 110 A, V _{GS} = 0 V,		56		ns
Reverse Recovery Charge	Qrr	di/dt = 100 A/μs		80		nC

TEST CIRCUIT 1 AVALANCHE CAPABILITY

$\begin{array}{c} \text{D.U.T.} \\ \text{RG} = 25 \ \Omega \\ \text{VGS} = 20 \rightarrow 0 \ \text{V} \end{array} \begin{array}{c} \text{D.U.T.} \\ \text{RG} \end{array} \begin{array}{c} \text{D.U.T.} \\ \text{NOD} \\ \text{NOD} \end{array}$



TEST CIRCUIT 2 SWITCHING TIME



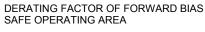
TEST CIRCUIT 3 GATE CHARGE

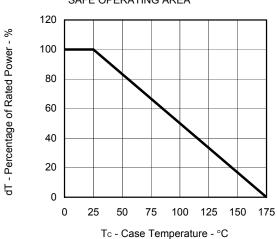
$$\begin{array}{c|c}
D.U.T. & \\
I_G = 2 \text{ mA} & \\
\hline
PG. & \\
\end{array}$$

$$\begin{array}{c|c}
PG. & \\
\end{array}$$

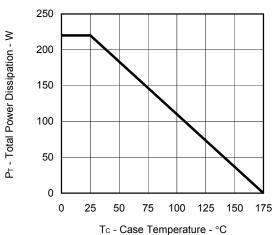
$$\begin{array}{c|c}
\end{array}$$

TYPICAL CHARACTERISTICS (TA = 25°C)

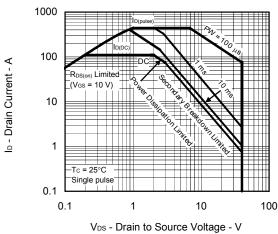




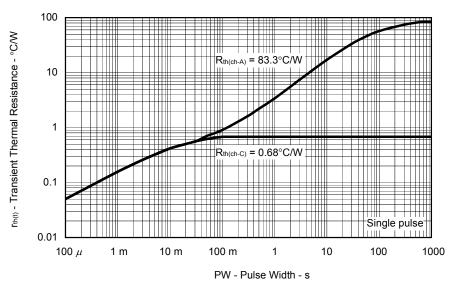
TOTAL POWER DISSIPATION vs. CASE TEMPERATURE

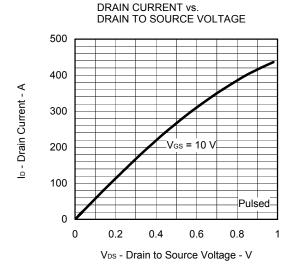


FORWARD BIAS SAFE OPERATING AREA

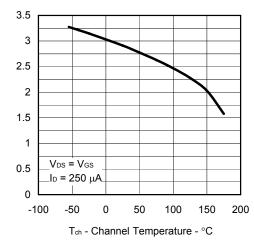




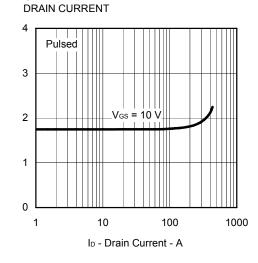




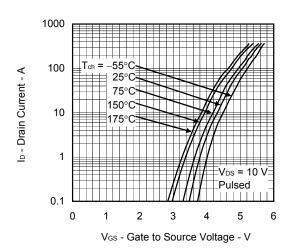




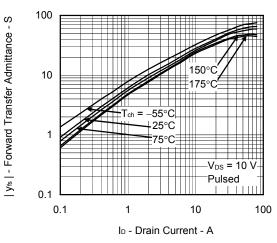
DRAIN TO SOURCE ON-STATE RESISTANCE vs.



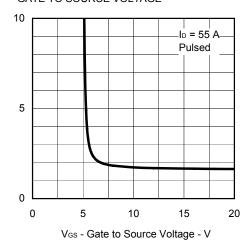
FORWARD TRANSFER CHARACTERISTICS



FORWARD TRANSFER ADMITTANCE vs. DRAIN CURRENT



DRAIN TO SOURCE ON-STATE RESISTANCE vs. GATE TO SOURCE VOLTAGE



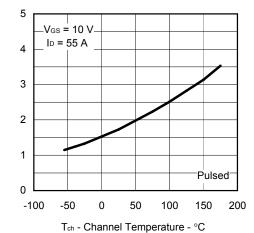
R_{DS(∞)} - Drain to Source On-state Resistance - mΩ

Ves(th) - Gate to Source Threshold Voltage - V

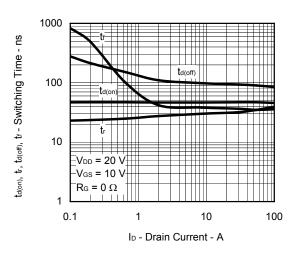
R_{DS(ση)} - Drain to Source On-state Resistance - mΩ

R_{DS(m)} - Drain to Source On-state Resistance - mΩ

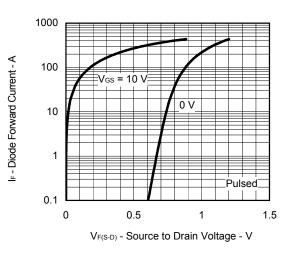
DRAIN TO SOURCE ON-STATE RESISTANCE vs. CHANNEL TEMPERATURE



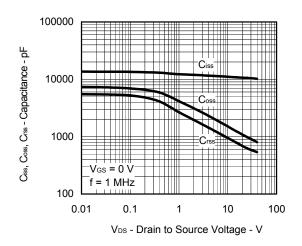
SWITCHING CHARACTERISTICS



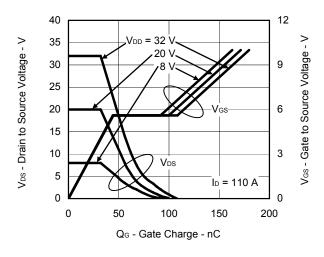
SOURCE TO DRAIN DIODE FORWARD VOLTAGE



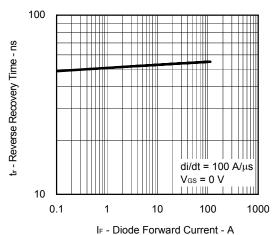
<R> CAPACITANCE vs. DRAIN TO SOURCE VOLTAGE



DYNAMIC INPUT/OUTPUT CHARACTERISTICS

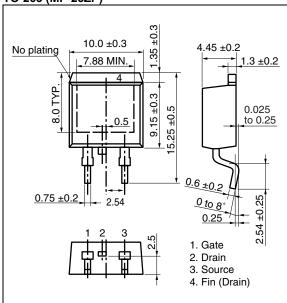


REVERSE RECOVERY TIME vs. DIODE FORWARD CURRENT

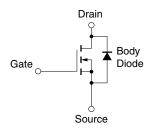


PACKAGE DRAWING (Unit: mm)

TO-263 (MP-25ZP)



EQUIVALENT CIRCUIT

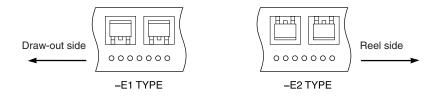


Remark Strong electric field, when exposed to this device, can cause destruction of the gate oxide and ultimately degrade the device operation. Steps must be taken to stop generation of static electricity as much as possible, and quickly dissipate it once, when it has occurred.

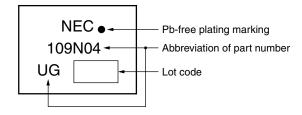
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TAPE INFORMATION

There are two types (-E1, -E2) of taping depending on the direction of the device.



MARKING INFORMATION



RECOMMENDED SOLDERING CONDITIONS

The NP109N04PUG should be soldered and mounted under the following recommended conditions.

For soldering methods and conditions other than those recommended below, please contact an NEC Electronics sales representative.

For technical information, see the following website.

Semiconductor Device Mount Manual (http://www.necel.com/pkg/en/mount/index.html)

Soldering Method	Soldering Conditions	Recommended Condition Symbol
Infrared reflow	Maximum temperature (Package's surface temperature): 260°C or below	IR60-00-3
	Time at maximum temperature: 10 seconds or less	
	Time of temperature higher than 220°C: 60 seconds or less	
	Preheating time at 160 to 180°C: 60 to 120 seconds	
	Maximum number of reflow processes: 3 times	
	Maximum chlorine content of rosin flux (percentage mass): 0.2% or less	
Partial heating	Maximum temperature (Pin temperature): 350°C or below	P350
	Time (per side of the device): 3 seconds or less	
	Maximum chlorine content of rosin flux: 0.2% (wt.) or less	

Caution Do not use different soldering methods together (except for partial heating).

NEC NP109N04PUG

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